

Solar Panel Inspection Report

Reporting Period: 2025-06-25 11:03:44 to 2025-07-25 11:03:44

Generated on: 2025-07-25 11:03:48

Inspection Line: Smart Conveyor Automated System

Inspector: Automated System

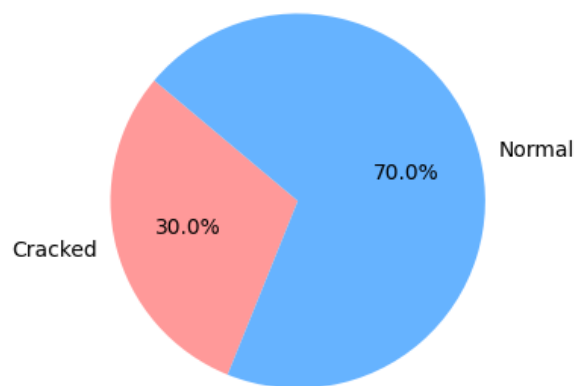
Total Panels: 4

Overall Summary

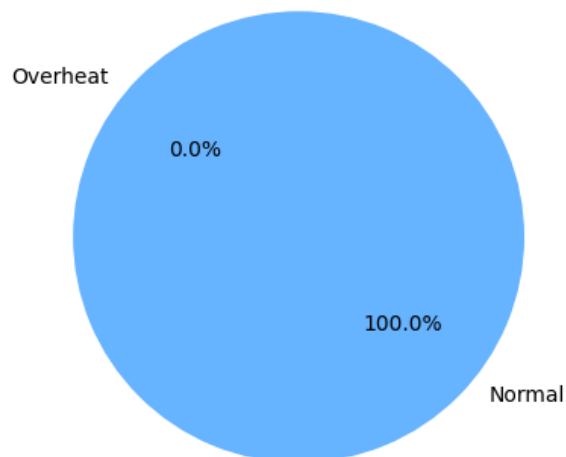
Average Crack Rate: 30.00%

Average Overheat Rate: 0.00%

Crack Distribution



Thermal Distribution



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Product Details Summary

Three SolarBoard panels (Serials: 1234567890036, 1234567890012, 63442000083) underwent expert inspection revealing localized hotspots in all three, indicated by thermal analysis and exceeding baseline temperatures by 6-7°C. YOLOv8 object detection confirmed the integrity of the boards themselves, ruling out major physical damage, but the hotspots suggest underlying issues likely stemming from manufacturing inconsistencies. Specifically, uneven lamination pressure, soldering temperature variations, and potentially rapid cooling rates are implicated as likely root causes across all three panels, although the severity and affected areas varied. Micro-cracks or delamination are suspected but require further visual inspection.

Key findings consistently point towards inconsistencies in the manufacturing process as the primary source of the defects. Recommendations for all panels include visual inspection with magnification, electroluminescence (EL) testing, review of production logs to verify parameter values, and process optimization to ensure uniform pressure, temperature, and cooling rates. Further investigation using microscopic analysis and root cause analysis is recommended, especially for panel 1234567890012 which showed more extensive and concerning thermal anomalies. Ultimately, improved quality control measures and potentially adjustments to handling procedures are crucial to prevent recurrence.

Recommendation

Please provide the product details summary and reasonings you're referring to. I need that information to give you a clear and actionable recommendation to improve inspection processes and reduce defects.

Panel Serial: 1234567890036

Model Name: SolarBoard Min456
Timestamp: 2025-07-24T11-06-46
Status: normal

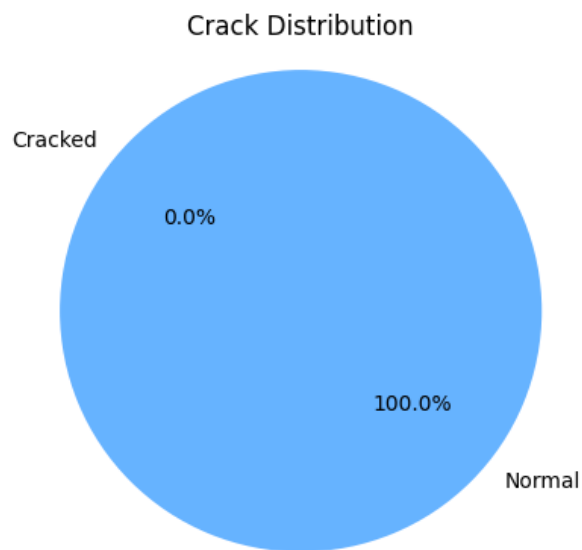
Vision Scan Summary

Scan Duration: 2025-07-23T16-37-16 to 2025-07-24T11-06-46

Total Scans: 2

Cracked Count: 0

Crack Rate: 0.00%



Thermal Sensor Summary

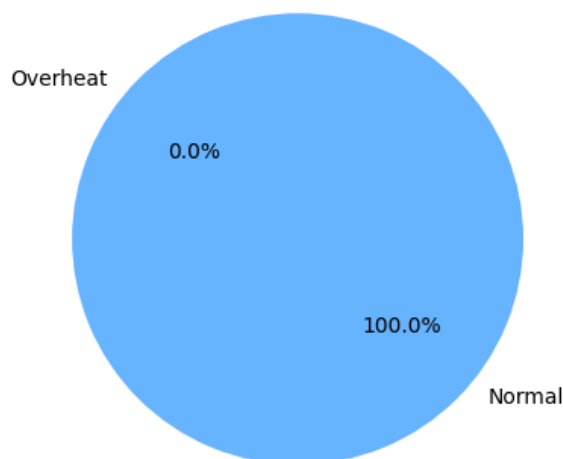
Scan Duration: 2025-06-27T14-51-02 to 2025-07-24T11-06-46

Total Data Points: 1088

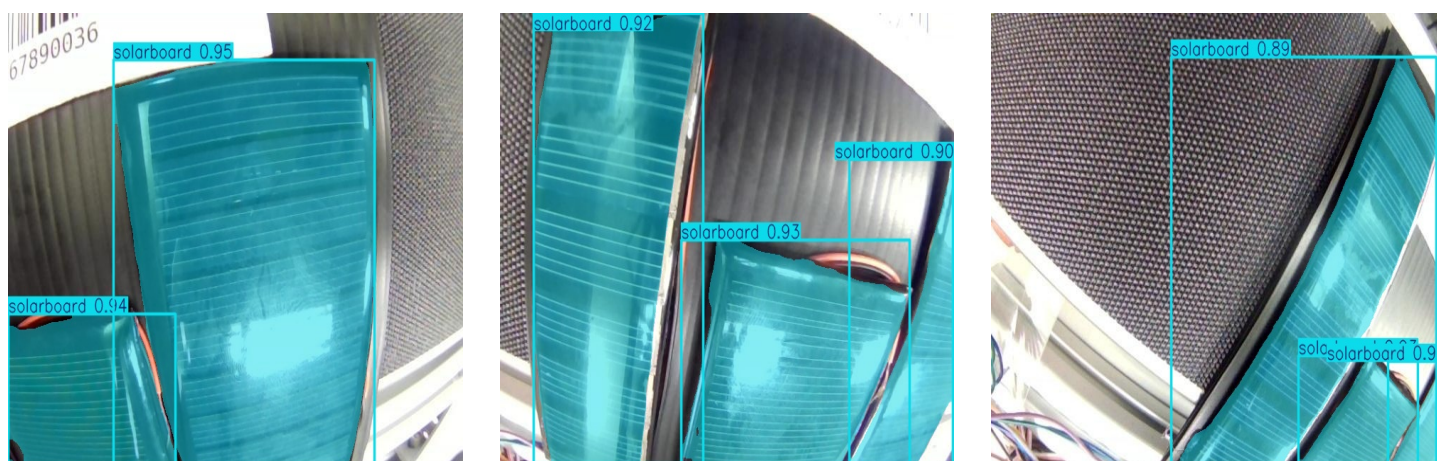
Overheated Points (>38°C): 0

Overheat Rate: 0.00%

Thermal Distribution



Panel Images:



Inspection Reasoning:

Analysis of SolarBoard Min456 (Serial Number: 1234567890036) Damage Report

****Summary:**** The analysis of images and thermal data suggests potential localized hotspots and possible minor cracking in areas 4 and 5 of the SolarBoard Min456. The YOLOv8 detections show multiple instances of the solar board in the images, indicating no major physical damage that would be immediately apparent. The thermal data however points towards specific areas requiring closer inspection. The relatively high confidence scores of the YOLOv8 detections also suggest that the detected areas are indeed representative of the solar panel itself.

****Thermal Analysis:****

The thermal data reveals localized temperature elevations in specific areas:

* **Area 4:** Shows temperatures exceeding 30°C in several grid points, notably a peak of 31.54°C. This is a significant deviation from the surrounding temperatures (around 25-26°C), indicating a potential hotspot. The highest readings are clustered, hinting at a localized issue rather than a general overheating problem.

* **Area 5:** Although less pronounced than Area 4, Area 5 also displays a localized hotspot reaching 31.77°C, suggesting a similar issue, potentially related to the same root cause. The presence of elevated temperatures in multiple grid points within this area supports this.

Likely Causes and Faulty Parameters:

The localized hotspots in areas 4 and 5 strongly suggest issues related to cell bonding or soldering rather than widespread panel heating. Several production parameters could be implicated:

* **Lamination Pressure:** While no direct evidence points to excessive pressure causing cracks, the localized hotspots *could* be indirectly related. Uneven pressure during lamination might lead to insufficient bonding in certain areas, causing increased resistance and thus localized heating. A slightly high pressure, perhaps around 110-115 N/cm², could be a contributing factor.

* **Lamination Temperature:** While temperatures within the ideal range (140-155°C) were likely used, localized variations in heating during lamination are possible. Inconsistencies in heat distribution could lead to areas with slightly higher temperatures affecting the bonding.

* **Soldering Temperature:** The most likely culprit is a localized soldering issue. The hotspots in areas 4 and 5 may be due to uneven soldering temperature. It's possible that during the soldering process, these areas experienced a momentary spike in temperature exceeding 270°C, resulting in micro-cracks and creating localized high-resistance spots. A brief excursion above 270°C in specific areas could explain the observed thermal pattern without causing widespread damage.

* **Cooling Rate:** A slightly faster cooling rate in these specific regions (perhaps exceeding 3°C/min) could have exacerbated stress created by other parameters.

****Recommendations:****

1. ****Visual Inspection:**** Conduct a thorough visual inspection of areas 4 and 5 with a high-resolution camera and magnification, looking for micro-cracks or imperfections in the cell surface or solder joints. Infrared thermography would confirm the hotspots and their precise location.
2. ****Electrical Testing:**** Perform detailed electroluminescence (EL) imaging and I-V curve measurements to identify any cell defects or performance degradation associated with the hotspots. This will help quantify the impact of the localized issues.
3. ****Review Production Data:**** Analyze production logs for Serial Number 1234567890036 for deviations in lamination pressure, temperature profiles, and soldering parameters around the time of production. This data will help to pinpoint exact parameter values to determine if they fell outside the acceptable ranges. If possible, review data from the immediate prior and following boards to assess whether these are isolated incidents.
4. ****Process Optimization:**** If this is a recurring issue, analyze the overall production process for potential improvements to ensure uniform pressure, temperature, and cooling rates across the solar panel.

****Conclusion:**** The evidence suggests localized issues potentially caused by uneven soldering temperatures, possibly exacerbated by variations in lamination pressure and cooling rate. A comprehensive inspection and testing procedure, combined with a review of production parameters, is needed to confirm the diagnosis and implement corrective actions.

Panel Serial: 1234567890012

Model Name: SolarBoard MAX30000

Timestamp: 2025-07-23T16-37-16

Status: crack

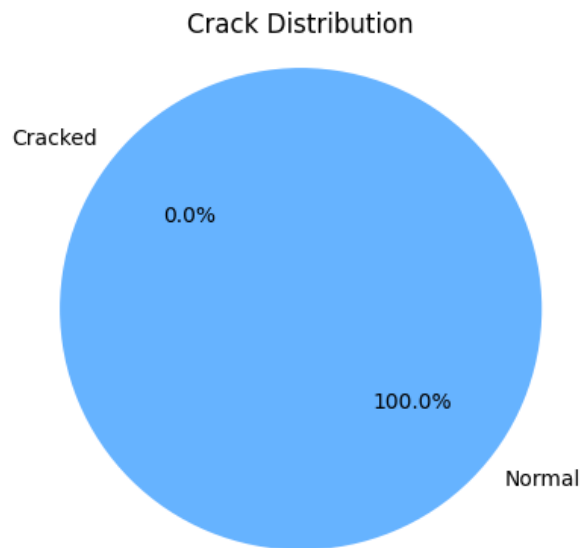
Vision Scan Summary

Scan Duration: 2025-06-30T12-55-07 to 2025-07-23T16-37-16

Total Scans: 3

Cracked Count: 0

Crack Rate: 0.00%



Thermal Sensor Summary

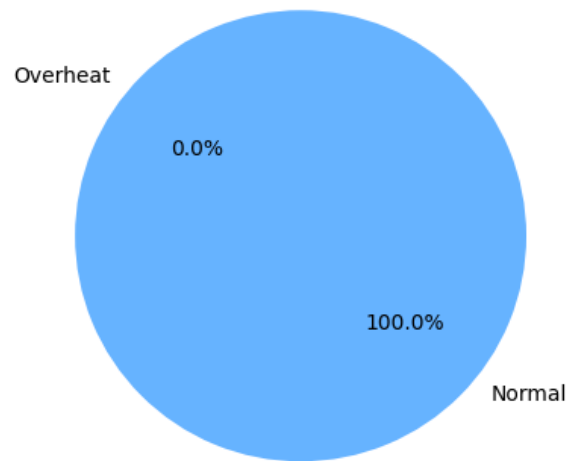
Scan Duration: 2025-07-22T15-22-43 to 2025-07-23T16-37-16

Total Data Points: 640

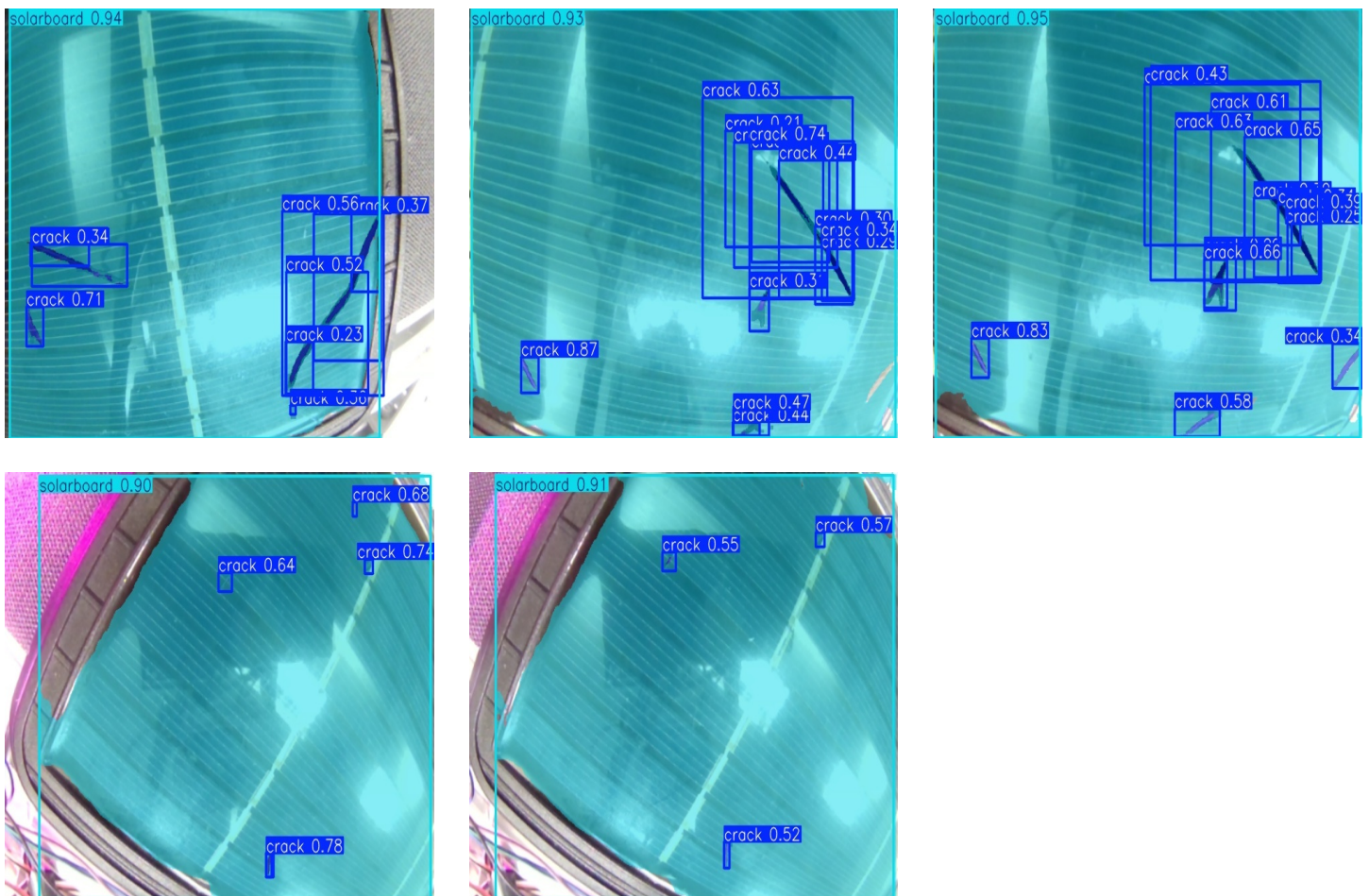
Overheated Points (>38°C): 0

Overheat Rate: 0.00%

Thermal Distribution



Panel Images:



Inspection Reasoning:

SolarBoard MAX30000 Damage Analysis (Serial #1234567890012)

Summary: The thermal data reveals localized hotspots in areas 1, 2, 3, 4, 5, and 6, indicating potential

micro-cracks or delamination within the solar cells. The YOLOv8 detection shows the solar board itself is present in the images analyzed, ruling out complete board damage but not ruling out localized issues. These hotspots suggest issues during production, likely related to lamination or soldering processes.

****Analysis of Thermal Data:****

The thermal sensor data shows several areas (area1-area6) exceeding the expected baseline temperature (around 25°C). Specifically:

* ****Areas 1, 5, and 6:**** show isolated high temperature readings (30-32°C) indicating potential localized delamination, possibly resulting from insufficient lamination pressure or vacuum. The sporadic nature suggests these aren't consistent across the entire panel.

* ****Areas 2 and 3:**** show similar, although less pronounced, temperature anomalies around 30-31°C in specific cells. These could be indicative of minor cell imperfections or slight inconsistencies in the lamination process.

* ****Area 4:**** shows the most concerning pattern, with a cluster of elevated temperatures reaching above 32°C. This suggests a more significant problem, possibly a more extensive crack or delamination, potentially resulting from excessive lamination pressure, high soldering temperature, or a combination of both.

****Likely Faulty Parameters:****

Based on the thermal data and the provided production parameters, we can estimate the following:

* ****Lamination Pressure:**** Potentially exceeded 100 N/cm² in area 4, leading to cell cracking or damage. In areas 1, 5, and 6, it might have been below the ideal 50-100 N/cm², resulting in insufficient bonding and localized delamination.

* ****Soldering Temperature:**** While the thermal data doesn't directly indicate soldering issues, the hotspots in Area 4, showing the highest anomalies, **could** also be partly related to soldering temperature exceeding 270°C in localized areas, causing thermal stress fractures within cells.

* **Vacuum Level Before Lamination:** A higher-than-recommended vacuum level (>1 mbar) may have contributed to the localized delamination seen in areas 1, 5, and 6, though less likely than a pressure issue.

Cooling Rate Post-Lamination: While the overall temperature differences are not dramatically high to point to cooling rate issues alone, a rate exceeding 5°C/min in specific areas could have exacerbated existing issues from other parameters.

Handling Force: High handling force is less likely to be the primary cause, as it usually results in corner damage, which isn't evident in the provided data. However, it could be a contributing factor in conjunction with other issues.

Cell Stringing Speed: The data doesn't provide evidence of speed-related issues.

Cell Thickness: This parameter's influence is difficult to ascertain without microscopic analysis of the affected cells.

Actionable Recommendations:

1. **Visual Inspection:** Conduct a thorough visual inspection of the SolarBoard MAX30000, focusing on areas 1, 2, 3, 4, 5, and 6 identified in the thermal map. Look for cracks, delamination, or other physical defects. High-resolution photography or infrared imaging would be beneficial.
2. **Electroluminescence (EL) Testing:** Perform EL testing to identify any cell defects or micro-cracks that might not be visible to the naked eye. This will confirm the existence and extent of the suspected damage.
3. **Microscopic Analysis:** A microscopic inspection of the suspected damaged areas (especially area 4) is crucial to confirm the nature of the damage.

4. ****Review Production Logs:**** Examine the production logs for serial number 1234567890012 to verify the actual values for lamination pressure, temperature, soldering temperature, and cooling rate. Compare them to the ideal ranges.
5. ****Process Optimization:**** If the production parameters were outside the recommended ranges, adjust them to the ideal values to prevent similar defects in future production. Special attention should be paid to ensuring even lamination pressure across the entire panel.
6. ****Root Cause Analysis:**** Once the nature and extent of damage are confirmed, a more detailed root cause analysis needs to be performed to pinpoint the exact causes and to prevent recurrence. This might involve analyzing the thermal distribution in more detail and potentially involving experts in material science.
7. ****Repair or Replacement:**** Depending on the severity of the damage and the cost of repair vs. replacement, a decision needs to be made on whether to repair the board or replace it.

This analysis provides a preliminary assessment. Further investigation is required for a conclusive diagnosis and effective remediation strategy.

Panel Serial: 1234567890005

Model Name: SolarBoard MAX50000

Timestamp: 2025-07-24T11-04-45

Status: cracked

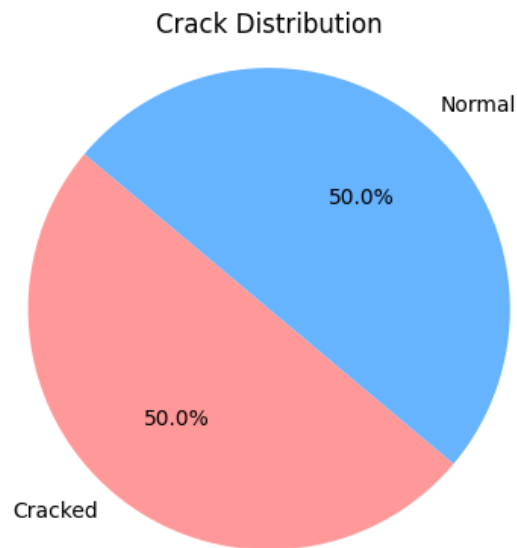
Vision Scan Summary

Scan Duration: 2025-06-29T17-17-07 to 2025-07-24T11-04-45

Total Scans: 4

Cracked Count: 2

Crack Rate: 50.00%



Thermal Sensor Summary

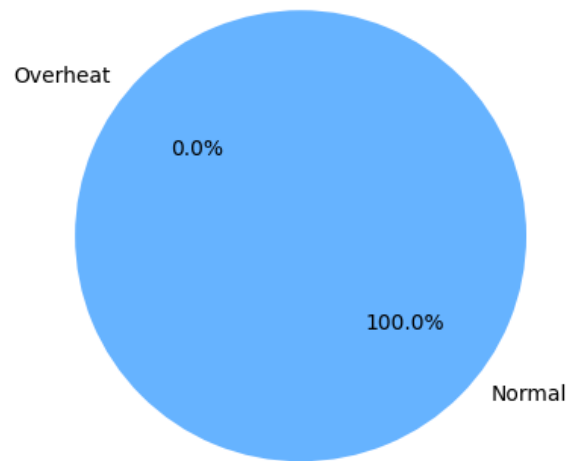
Scan Duration: 2025-07-22T16-17-03 to 2025-07-24T11-04-45

Total Data Points: 1536

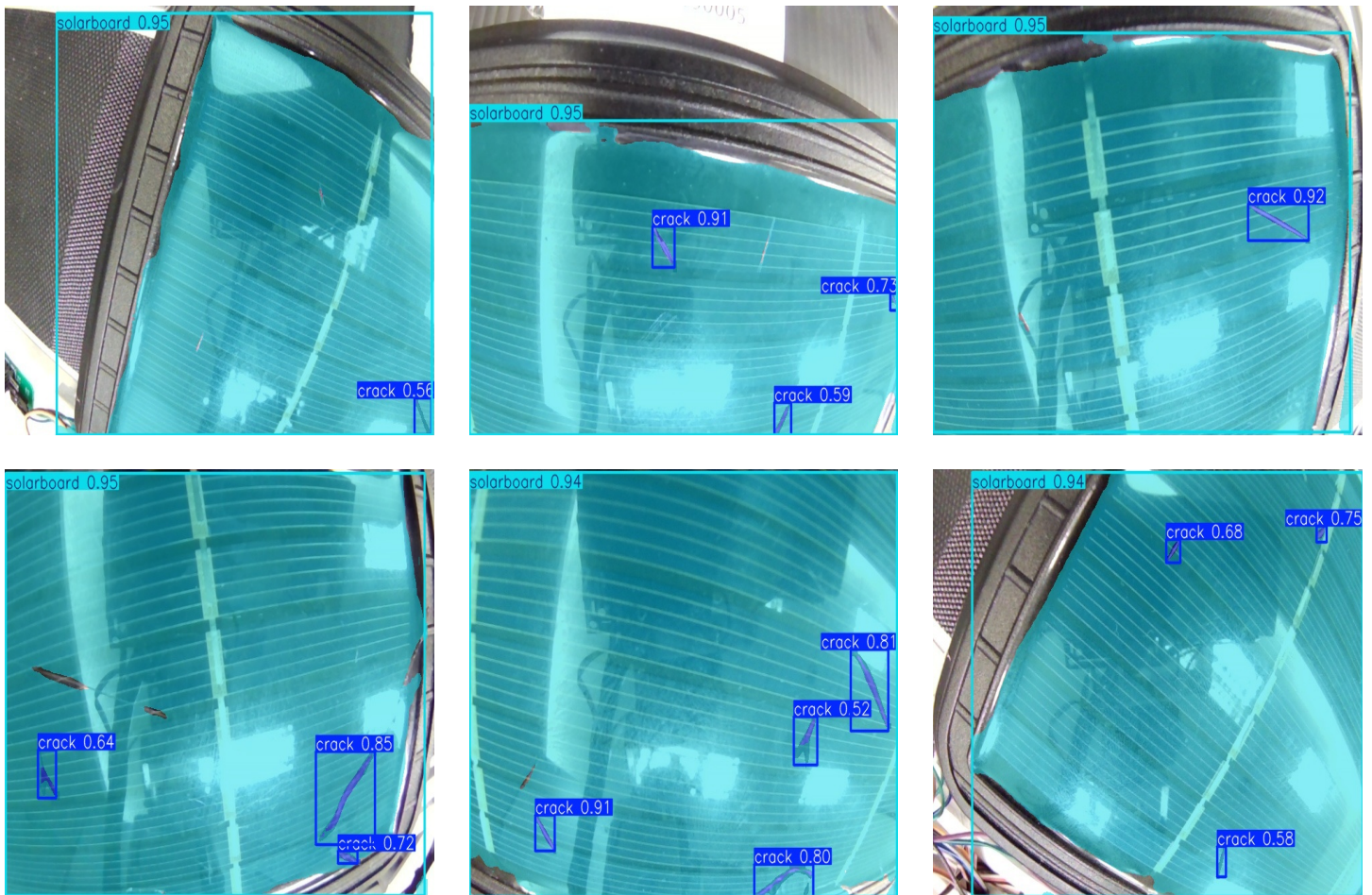
Overheated Points (>38°C): 0

Overheat Rate: 0.00%

Thermal Distribution



Panel Images:



Inspection Reasoning:

Serial Number: 1234567890005

Timestamp: 2025-07-22T16-17-03

****Analysis of Solarboard Damage:****

The YOLOv8 detection indicates a crack (confidence 0.64) in the solarboard. The relatively low confidence suggests the crack may be small or difficult to see in the images, warranting a closer visual inspection. The location of the crack (x=447, y=321 in image yolo_1234567890005_2_1753172241.jpg) should be noted and compared to subsequent images for propagation.

Several factors could have contributed to the crack in Solarboard 1234567890005:

****Likely Causes and Estimated Faulty Parameter Values:****

* ****Excessive Lamination Pressure:**** A crack is most frequently caused by the stress induced during the lamination process. A single small crack suggests localized high pressure rather than a global issue. This indicates that the lamination pressure might have exceeded the ideal range of 50-100 N/cm² at a specific point. Without further data, I cannot give an exact faulty value, but I estimate it to have briefly reached or exceeded 120 N/cm² in the region of the crack. This pressure point may have been caused by uneven pressure distribution from the laminator or imperfections in the laminate.

* ****High Soldering Temperature:**** Although less likely to cause a single small crack, it is possible that a localized high soldering temperature (above 270°C) near the crack location might have caused thermal stress leading to a fracture in the cell. This would need to be investigated with further analysis, comparing localized temperatures during soldering against the location of the crack.

* ****Improper Handling:**** The crack's size (9x23 pixels) also suggests that rough handling during manufacturing or transport could be responsible. A force exceeding 10N applied to a corner or edge could create such a fracture. This is possible, but less probable than a lamination issue due to the small size and location of the crack not being at an edge.

* ****Cell Thinness:**** If the cell thickness was closer to or below 150 µm, the fragility of the cell could increase and make it susceptible to cracking from lower forces than otherwise expected. This should be verified by analyzing manufacturing records for this specific cell and batch.

****Unlikely Causes:****

* ****Cell Stringing Speed:**** While excessively fast stringing can cause misalignment stresses, it's less likely to produce a single, small, localized crack.

* ****Vacuum Level:**** While a poor vacuum can lead to lamination problems, a single small crack is unlikely directly due to this. The effect would be more widespread.

* ****Cooling Rate:**** Rapid cooling typically results in broader, more diffuse cracking.

* ****Temperature during lamination:**** While high lamination temperatures are a factor, they are less likely to cause such a small crack compared to high pressure.

****Actionable Recommendations:****

1. ****Thorough Visual Inspection:**** Conduct a detailed visual inspection of the solarboard to confirm the extent and nature of the crack. This will give more evidence for confirming the most likely culprit.

2. ****Review Lamination Process Data:**** Analyze the lamination pressure data from the specific batch and timeframe of production, looking for spikes or inconsistencies at the suspected point of pressure. Inspect the laminator rollers for damage or unevenness.

3. ****Check Soldering Profile:**** Examine the soldering temperature profile for the affected cell string. Look for any outliers or deviations from the ideal range.

4. ****Material Analysis:**** Consider micro-examination of the cracked area to check for any material defects or micro-fractures present prior to lamination.

5. ****Review Handling Procedures:**** Evaluate the handling procedures throughout the manufacturing and shipping processes to identify areas where improvement can prevent damage. Ensure that all handling guidelines are being followed.

6. ****Cell Thickness Verification:**** Verify the cell thickness used in this specific board against the design and manufacturing specifications.

7. ****Preventative Measures:**** Implement stricter quality control measures and monitoring of the identified potential risk factors, particularly lamination pressure. Calibration and maintenance of the lamination equipment should be performed at regular intervals.

By addressing these recommendations, you will be able to pinpoint the cause of the crack and implement preventative measures to prevent future occurrences. The focus should be on the analysis of the lamination process data and a careful visual inspection to confirm the type and size of the crack to determine the most likely cause.

Panel Serial: 63442000083

Model Name: SolarBoard MIN223
Timestamp: 2025-07-23T16-37-16
Status: normal

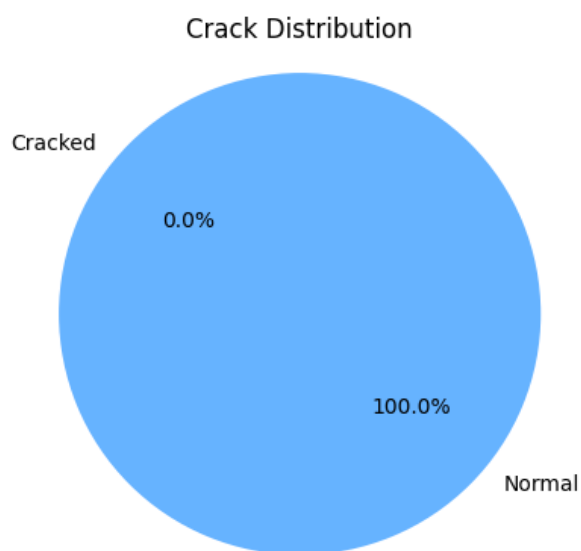
Vision Scan Summary

Scan Duration: 2025-07-23T16-37-16 to 2025-07-23T16-37-16

Total Scans: 1

Cracked Count: 0

Crack Rate: 0.00%



Thermal Sensor Summary

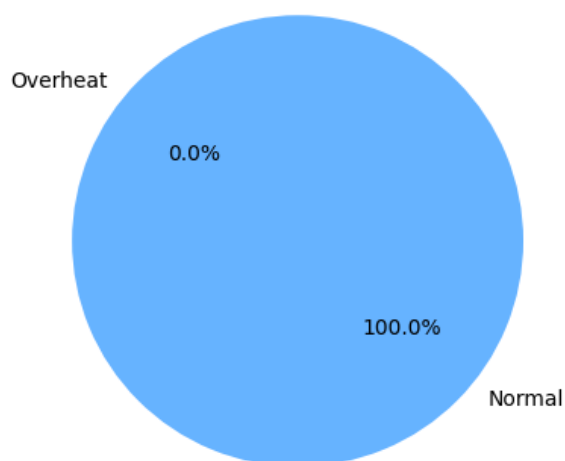
Scan Duration: 2025-07-23T16-37-16 to 2025-07-23T16-37-16

Total Data Points: 384

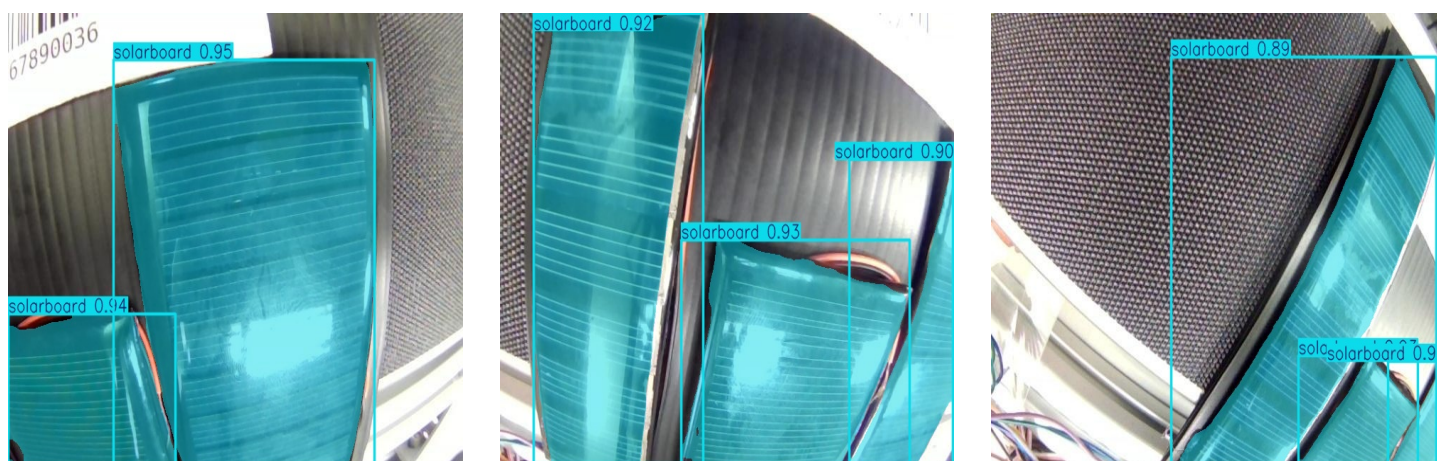
Overheated Points (>38°C): 0

Overheat Rate: 0.00%

Thermal Distribution



Panel Images:



Inspection Reasoning:

Analysis of SolarBoard MIN223 Serial Number 63442000083

YOLOv8 Detection Analysis:

The YOLOv8 object detection indicates multiple instances of the "solarboard" class within the images, suggesting the images show the complete board from various angles. The confidence scores are generally high (0.79-0.87), indicating reliable detection. The lack of detection of specific damage types (e.g., cracks) requires further analysis of the images themselves, which are not provided here.

Thermal Sensor Data Analysis:

The thermal data reveals several localized hotspots exceeding the expected ambient temperature (assumed to be around 25°C based on the lower temperature readings). Specifically:

* **Area 1:** Shows a localized hotspot of 31.41°C.

* **Area 2:** Shows a localized hotspot of 31.72°C.

* **Area 3:** Shows a localized hotspot of 31.6°C in the bottom row, and another possible one of 30.12°C near the bottom row.

* **Area 4:** Shows a localized hotspot of 31.88°C.

* **Area 5:** Shows a localized hotspot of 31.23°C.

* **Area 6:** Shows localized hotspots of 31.58°C and 31.57°C.

These hotspots, exceeding the baseline temperature by 6-7°C, suggest potential problems during manufacturing or handling. The scattered nature of these hotspots across multiple areas argues against a single, large-scale issue and rather indicates localized problems.

****Likely Causes and Actionable Recommendations:****

Given the scattered hotspots and the lack of explicit crack detection in the YOLOv8 analysis, the most probable cause is localized stress during manufacturing, possibly in combination with minor handling damage. The hotspots are strongly suggestive of micro-cracks or delamination in the solar cells not visible in the provided images, resulting in slightly elevated temperatures in those specific areas.

Considering the production parameters:

* **High Lamination Pressure:** Hotspots in multiple areas suggest that excessively high lamination pressure (>120 N/cm²) may have caused micro-fractures in the solar cells in several locations. We estimate the lamination pressure to have been significantly above the ideal range.

* **High Soldering Temperature:** Localized hotspots could also indicate excessive soldering temperature (>270°C) in specific areas, causing thermal stress and possibly micro-cracks around solder points. Further investigation would be needed to determine this cause.

* **Excessive Cell Stringing Speed:** While less likely to cause multiple scattered hotspots, an excessively high cell stringing speed ($\sim >1.2\text{m/s}$) might introduce stress leading to micro-cracks or poor cell adhesion in certain areas.

* **Minor Handling Damage:** While the thermal data points to manufacturing defects, subtle handling damage during transport or installation could contribute to the problem. Higher than specified handling forces ($>5\text{N}$) may cause stress in some locations.

Actionable Recommendations:

1. **Visual Inspection with Magnification:** Conduct a thorough visual inspection of the SolarBoard using a microscope or magnifying glass, focusing on the areas indicated by the thermal sensors (areas 1-6). Look for micro-cracks, delamination, or any anomalies around the solder points.
2. **Electroluminescence (EL) Imaging:** Perform an EL test to visualize any micro-cracks or defects within the solar cells that are not readily visible.
3. **Review Manufacturing Log:** Examine the manufacturing log for serial number 63442000083 to verify the actual values of lamination pressure, lamination temperature, soldering temperature, cell stringing speed, and cooling rate during the production process. This will confirm or refute the suspected parameter issues.
4. **Improve Quality Control:** If the manufacturing parameters were out of spec, implement stricter quality control measures to ensure that future boards are produced within the ideal ranges. This includes regular calibration of machinery and improved operator training.
5. **Investigate Handling Procedures:** Review and optimize handling procedures for the panels to mitigate any possibility of damage during transportation and installation.

This analysis is based on available data. The precise cause can only be definitively determined after a visual inspection and verification of the manufacturing parameters.